

ZXMC3F31DN8 30V SO8 Complementary dual enhancement mode MOSFET

Summary

Device	V _{(BR)DSS} (V)	Q _G (nC)	$R_{DS(on)}\left(\Omega\right)$	I _D (A)
Q1	30	12.9	0.024 @ V _{GS} = 10V	7.3
			0.039 @ V _{GS} = 4.5V	5.7
Q2	-30	12.7	0.045 @ V _{GS} = -10V	5.3
			0.080 @ V _{GS} = -4.5V	4



Description

This new generation Trench MOSFET from Zetex has been designed to minimize the on-state resistance ($R_{DS(on)}$) and yet maintain superior switching performance making it ideal for power management and battery charging functions.

Features

- · Low on-resistance
- 4.5V gate drive capability
- · Low profile SOIC package

Applications

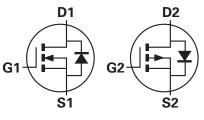
- DC-DC Converters
- SMPS
- · Load switching switches
- Motor control
- Backlighting

Ordering information

Device	Reel size (inches) Tape width (mm)		Quantity per reel	
ZXMC3F31DN8TA	7	12	500	

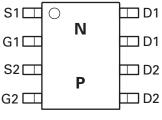
Device marking

ZXMC 3F31



Q1 N-Channel

Q2 P-Channel



Top view

Absolute maximum ratings

Parameter	Symbol	N- channel Q1	P- channel Q2	Unit
Drain-Source voltage	V_{DSS}	30	-30	V
Gate-Source voltage	V _{GS}	±20	±20	V
Continuous Drain current @ V_{GS} = 10V; T_A =25°C $(b)(d)$ @ V_{GS} = 10V; T_A =70°C $(b)(d)$	I _D	7.3 5.9	5.3 4.3	А
@ V_{GS} = 10V; T_A =25°C (a)(d) @ V_{GS} = 10V; T_A =25°C (a)(e) @ V_{GS} = 10V; T_L =25°C (f)(d)		5.7 6.8 7.8	4.1 4.9 5.7	
Pulsed Drain current ^(c)	I _{DM}	33	23	Α
Continuous Source current (Body diode) (b)(d)	I _S	3.5	3.2	Α
Pulsed Source current (Body diode) (c)(d)	I _{SM}	33	23	Α
Power dissipation at T _A =25°C (a)(d) Linear derating factor	P _D		25 0	W mW/°C
Power dissipation at T _A =25°C (a)(e) Linear derating factor	P _D		.8 4	W mW/°C
Power dissipation at T _A =25°C (b)(d) Linear derating factor	P _D		.1 7	W mW/°C
Power dissipation at T _L =25°C (f) (d) Linear derating factor	P _D		35 9	W mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 t	o 150	°C

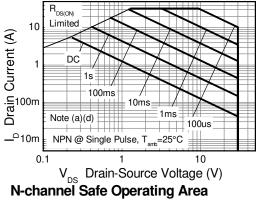
Thermal resistance

Parameter	Symbol	Value	Unit	
Junction to ambient ^{(a)(d)}	$R_{ heta JA}$	100	°C/W	
Junction to ambient (a)(e)	$R_{ heta JA}$	70	°C/W	
Junction to ambient (b)(d)	$R_{ heta JA}$	60	°C/W	
Junction to lead (f) (d)	$R_{ hetaJL}$	53	°C/W	

NOTES:

- (a) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.
- (b) Mounted on FR4 PCB measured at $t \le 10$ sec.
- (c) Repetitive rating on 25mm x 25mm FR4 PCB, D=0.02, pulse width 300us pulse width limited by maximum junction temperature.
- (d) For a device with one active die.
- (e) For a device with two active die running at equal power.(f) Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal characteristics

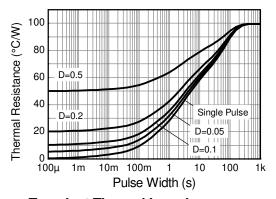


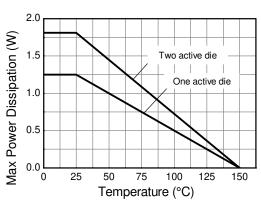
Drain Current (A) 100ms Note (a)(d) __^10m PNP @ Single Pulse, Tal

Limited

10

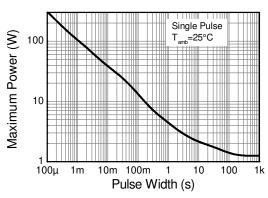
 $-V_{_{
m DS}}$ Drain-Source Voltage (V) P-channel Safe Operating Area





Transient Thermal Impedance

Derating Curve



Pulse Power Dissipation

ZXMC3F31DN8

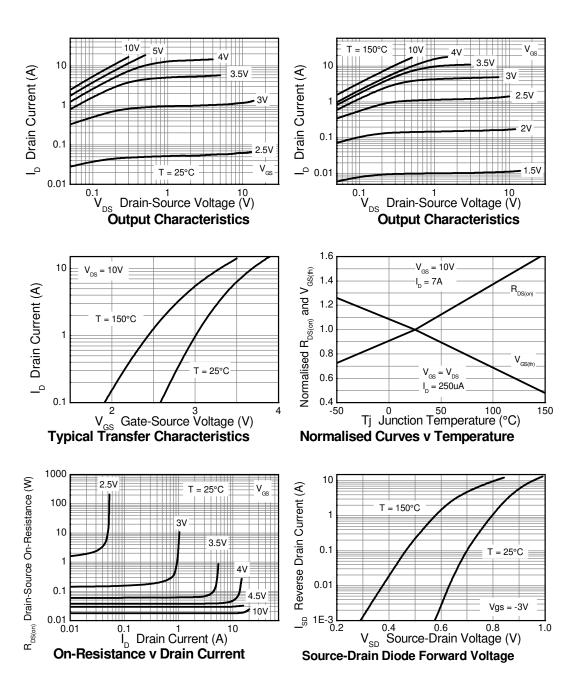
Q1 N-channel electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-Source breakdown voltage	V _{(BR)DSS}	30			V	$I_D = 250 \mu A, V_{GS} = 0 V$
Zero Gate voltage Drain current	I _{DSS}			0.5	μА	V _{DS} =30V, V _{GS} =0V
Gate-Body leakage	I _{GSS}			100	nA	$V_{GS}=\pm20V, V_{DS}=0V$
Gate-Source threshold voltage	V _{GS(th)}	1.0		3.0	V	$I_D=250\mu A,\ V_{DS}=V_{GS}$
Static Drain-Source on-state resistance (*)	R _{DS(on)}			0.024 0.039	Ω	V_{GS} = 10V, I_{D} = 7.0A V_{GS} = 4.5, I_{D} = 6.0A
Forward Transconductance (*) (†)	g _{fs}		16.5		S	V _{DS} = 15V, I _D = 7.0A
Dynamic (†)				•		
Input capacitance	C _{iss}		608		pF	
Output capacitance	C _{oss}		132		pF	V _{DS} = 15V, V _{GS} =0V
Reverse transfer capacitance	C _{rss}		72		pF	f=1MHz
Switching (‡) (†)						
Turn-on-delay time	t _{d(on)}		2.9		ns	
Rise time	t _r		3.3		ns	V _{DD} = 15V, V _{GS} =10V
Turn-off delay time	t _{d(off)}		16		ns	I _D = 1A
Fall time	t _f		8		ns	$R_G \cong 6.0\Omega$,
Total Gate charge	Qg		12.9		nC	
Gate-Source charge	Q _{gs}		2.5		nC	V _{DS} = 15V, V _{GS} = 10V
Gate-Drain charge	Q _{gd}		2.52		nC	- I _D = 7A
Source-Drain diode			ı	1	1	1
Diode forward voltage (*)	V_{SD}		0.82	1.2	V	I _S = 1.7A,V _{GS} =0V
Reverse recovery time (‡)	t _{rr}		12		ns	- I _S = 2.2A,di/dt=100A/μs
Reverse recovery charge ^(‡)	Q _{rr}		4.8		nC	15- 2.2Λ,α//αι-100Α/μ5

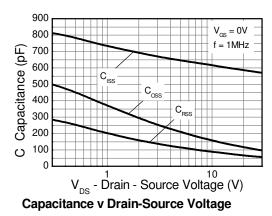
NOTES:

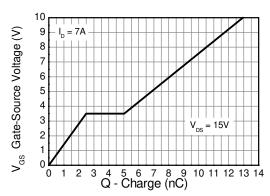
^(*) Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%. (†)Switching characteristics are independent of operating junction temperature. (‡)For design aid only, not subject to production testing

Q1 Typical characteristics



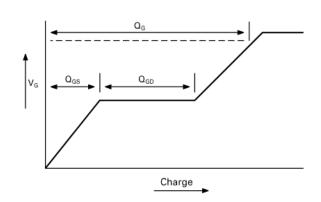
Q1 Typical characteristics -cntd.

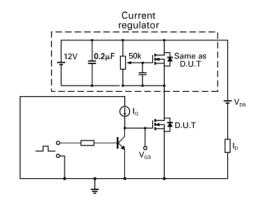




Gate-Source Voltage v Gate Charge

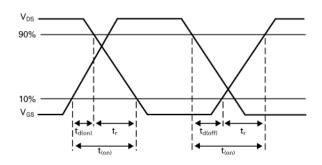
Test circuits

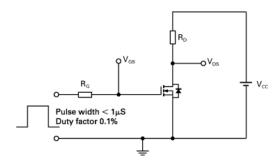




Basic gate charge waveform

Gate charge test circuit





Switching time waveforms

Switching time test circuit

ZXMC3F31DN8

Q2 P-channel electrical characteristics (at $T_{amb} = 25$ °C unless otherwise stated)

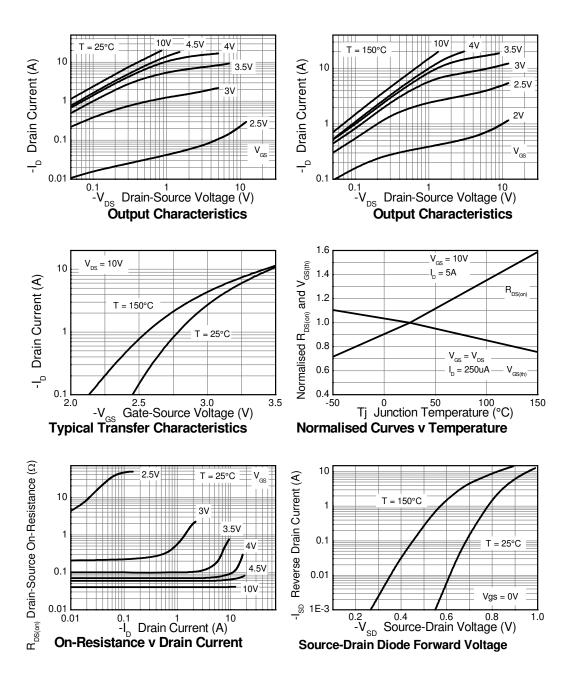
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-Source breakdown voltage	V _{(BR)DSS}	-30			V	$I_D = -250 \mu A, V_{GS} = 0 V$
Zero Gate voltage Drain current	I _{DSS}			-5.0	μА	V _{DS} =-30V, V _{GS} =0V
Gate-Body leakage	I _{GSS}			-100	nA	$V_{GS}=\pm20V, V_{DS}=0V$
Gate-Source threshold voltage	V _{GS(th)}	-1.0		-3.0	V	I_{D} = -250 μ A, V_{DS} = V_{GS}
Static Drain-Source on-state resistance ^(*)	R _{DS(on)}			0.045 0.080	Ω	V _{GS} = -10V, I _D = -5.0A V _{GS} = -4.5V, I _D = -4.0A
Forward Transconductance (*) (†)	g _{fs}		14		S	V _{DS} = -15V, I _D = -5.0A
Dynamic (†)						
Input capacitance	C _{iss}		670		pF	
Output capacitance	C _{oss}		126		pF	V_{DS} = -15V, V_{GS} =0V
Reverse transfer capacitance	C _{rss}		70		pF	f=1MHz
Switching (‡) (†)					•	
Turn-on-delay time	t _{d(on)}		1.9		ns	
Rise time	t _r		3		ns	V _{DD} = -15V, V _{GS} =-10V
Turn-off delay time	t _{d(off)}		30		ns	I _D = -1A
Fall time	t _f		21		ns	$R_G \cong 6.0\Omega$,
Total Gate charge	Qg		12.7		nC	
Gate-Source charge	Q _{gs}		2		nC	V _{DS} = -15V, V _{GS} = -10V
Gate-Drain charge	Q _{gd}		2.4		nC	I _D = -5A
Source-Drain diode	1		•		·	•
Diode forward voltage (*)	V _{SD}		-0.82	-1.2	V	I _S = -2A,V _{GS} =0V
Reverse recovery time (‡)	t _{rr}		16.5		ns	I _S = -2.1A,di/dt=100A/μs
Reverse recovery charge ^(‡)	Q _{rr}		11.5		nC	13- 2.17 , αι/αι-1007 / μ3

NOTES:

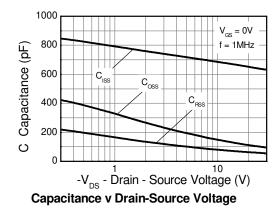
^(*) Measured under pulsed conditions. Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$. (†)Switching characteristics are independent of operating junction temperature.

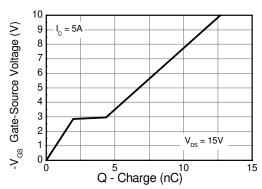
^(‡)For design aid only, not subject to production testing

Typical characteristics



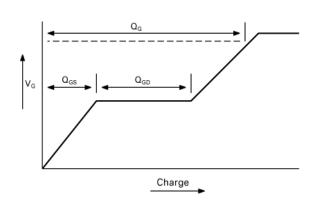
Typical characteristics

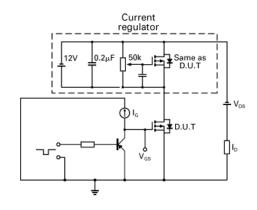




Gate-Source Voltage v Gate Charge

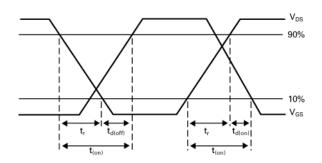
Test circuits

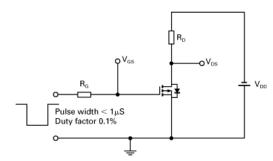




Basic gate charge waveform

Gate charge test circuit

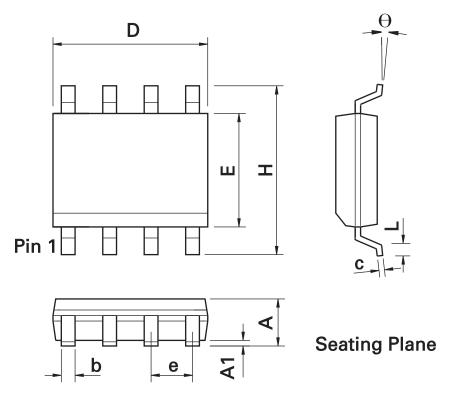




Switching time waveforms

Switching time test circuit

Package outline SO8



SO8 Package Information

DIM	Inches		Millimeters		DIM	Inc	hes	Millim	neters
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	U	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

ZXMC3F31DN8

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